

FDFS2P103A

Integrated P-Channel PowerTrench® MOSFET and Schottky Diode

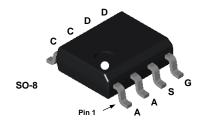
General Description

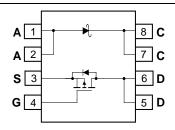
The FDFS2P103A combines the exceptional performance of Fairchild's PowerTrench MOSFET technology with a very low forward voltage drop Schottky barrier rectifier in an SO-8 package.

This device is designed specifically as a single package solution for DC to DC converters. It features a fast switching, low gate charge MOSFET with very low onstate resistance. The independently connected Schottky diode allows its use in a variety of DC/DC converter topologies.

Features

- -5.3 A, -30V $R_{DS(ON)} = 59 \text{ m}\Omega$ @ $V_{GS} = -10 \text{ V}$ $R_{DS(ON)} = 92 \text{ m}\Omega$ @ $V_{GS} = -4.5 \text{ V}$
- V_F < 0.35 V @ 1 A (T_J = 125°C)
 V_F < 0.25 V @ 1 A (T_J = 25°C)
- Schottky and MOSFET incorporated into single power surface mount SO-8 package
- Electrically independent Schottky and MOSFET pinout for design flexibility





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	MOSFET Drain-Source Voltage		-30	V
V _{GSS}	MOSFET Gate-Source Voltage		±25	V
I _D	Drain Current - Continuous	(Note 1a)	-5.3	А
	- Pulsed		-20	
P _D	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		−55 to +150	°C
V _{RRM}	Schottky Repetitive Peak Reverse Voltage		30	V
Io	Schottky Average Forward Current	(Note 1a)	1	А

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDFS2P103A	FDFS2P103A	13"	12mm	2500 units

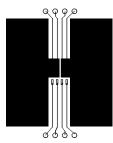
$\begin{array}{c c} \underline{ABV_{DSS}} \\ \underline{AT_J} \\ \underline{C} \\ C$	Drain-Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage	$\begin{split} &V_{GS} = 0 \text{ V}, & I_D = -250 \mu\text{A} \\ &I_D = -250 \mu\text{A}, \\ &Referenced to 25^{\circ}\text{C} \\ &V_{DS} = -24 \text{ V}, &V_{GS} = 0 \text{ V} \\ &V_{GS} = \pm 25 \text{ V}, &V_{DS} = 0 \text{ V} \\ \end{split}$ $\begin{aligned} &V_{DS} = V_{GS}, &I_D = -250 \mu\text{A} \\ &I_D = -250 \mu\text{A}, \\ &Referenced to 25^{\circ}\text{C} \\ &V_{GS} = -10 \text{ V}, &I_D = -5.3 \text{ A} \\ &V_{GS} = -4.5 \text{ V}, &I_D = -4 \text{ A} \\ &V_{GS} = -10 \text{ V}, &I_D = -5.3 \text{ A} \end{aligned}$ $\begin{aligned} &V_{DS} = -5 \text{ V}, &I_D = -5.3 \text{ A} \end{aligned}$	-30 -1	-1.8 4.2 50 76 68 8.9	-1 ±100	V mV/°C μA nA V mV/°C
BV _{DSS}	Drain—Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate—Body Leakage Cteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Gemperature Coefficient Static Drain—Source Dn—Resistance Characteristics nput Capacitance	$\begin{split} I_D &= -250 \ \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{DS} &= -24 \ \text{V}, V_{GS} = 0 \ \text{V} \\ V_{GS} &= \pm 25 \ \text{V}, V_{DS} = 0 \ \text{V} \\ \end{split}$ $\begin{aligned} V_{DS} &= V_{GS}, I_D = -250 \ \mu\text{A} \\ I_D &= -250 \ \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{GS} &= -10 \ \text{V}, I_D = -5.3 \ \text{A} \\ V_{GS} &= -4.5 \ \text{V}, I_D = -4 \ \text{A} \\ V_{GS} &= -10 \ \text{V}, I_D = -5.3 \ \text{A} \end{aligned}$ $\begin{aligned} V_{DS} &= -5 \ \text{V}, I_D = -5.3 \ \text{A} \end{aligned}$		-1.8 4.2 50 76 68	±100 -3 59 92	mV/°C μA nA V mV/°C
ABV _{DSS}	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate—Body Leakage Cteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Femperature Coefficient Static Drain—Source Dn—Resistance Characteristics nput Capacitance	$\begin{split} I_D &= -250 \ \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{DS} &= -24 \ \text{V}, V_{GS} = 0 \ \text{V} \\ V_{GS} &= \pm 25 \ \text{V}, V_{DS} = 0 \ \text{V} \\ \end{split}$ $\begin{aligned} V_{DS} &= V_{GS}, I_D = -250 \ \mu\text{A} \\ I_D &= -250 \ \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{GS} &= -10 \ \text{V}, I_D = -5.3 \ \text{A} \\ V_{GS} &= -4.5 \ \text{V}, I_D = -4 \ \text{A} \\ V_{GS} &= -10 \ \text{V}, I_D = -5.3 \ \text{A} \end{aligned}$ $\begin{aligned} V_{DS} &= -5 \ \text{V}, I_D = -5.3 \ \text{A} \end{aligned}$	-1	-1.8 4.2 50 76 68	±100 -3 59 92	μA nA V mV/°C
IDSS	Zero Gate Voltage Drain Current Gate—Body Leakage Cteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Temperature Coefficient Static Drain—Source Dn—Resistance Characteristics nput Capacitance	$\begin{split} V_{DS} = -24 \ V, & V_{GS} = 0 \ V \\ V_{GS} = \pm 25 \ V, & V_{DS} = 0 \ V \\ \end{split}$ $\begin{aligned} V_{DS} = V_{GS}, & I_{D} = -250 \ \mu A \\ I_{D} = -250 \ \mu A, & Referenced to 25^{\circ}C \\ V_{GS} = -10 \ V, & I_{D} = -5.3 \ A \\ V_{GS} = -4.5 \ V, & I_{D} = -4 \ A \\ V_{GS} = -10 \ V, & I_{D} = -5.3 \ A \end{aligned}$ $\begin{aligned} V_{DS} = -5V, & I_{D} = -5.3 \ A \end{aligned}$	-1	-1.8 4.2 50 76 68	±100 -3 59 92	μA nA V mV/°C
Con	Gate-Body Leakage Cteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Gemperature Coefficient Static Drain-Source Dn-Resistance Characteristics nput Capacitance	$\begin{split} V_{GS} = \pm 25 \ V, & V_{DS} = 0 \ V \\ \\ V_{DS} = V_{GS}, & I_{D} = -250 \ \mu A \\ I_{D} = -250 \ \mu A, \\ Referenced to 25^{\circ}C \\ V_{GS} = -10 \ V, & I_{D} = -5.3 \ A \\ V_{GS} = -4.5 \ V, & I_{D} = -4 \ A \\ V_{GS} = -10 \ V, & I_{D} = -5.3 \ A \\ \end{split}$	-1	4.2 50 76 68	±100 -3 59 92	NA V mV/°C
$ \begin{array}{c c} \textbf{On Charac} \\ \textbf{V}_{\text{GS(th)}} & \textbf{G} \\ \hline \Delta \textbf{V}_{\text{GS(th)}} & \textbf{G} \\ \Delta \textbf{T}_{\text{J}} & \textbf{T} \\ \textbf{R}_{\text{DS(on)}} & \textbf{S} \\ \textbf{G} \\ \textbf{G} \\ \textbf{S} \\ \textbf{G} \\ \textbf{G} \\ \textbf{Switching} \\ \end{array} $	Cteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Femperature Coefficient Static Drain—Source Dn—Resistance Characteristics nput Capacitance	$\begin{split} &V_{DS} = V_{GS}, &I_{D} = -250 \ \mu\text{A} \\ &I_{D} = -250 \ \mu\text{A}, \\ &Referenced \ to \ 25^{\circ}\text{C} \\ &V_{GS} = -10 \ \text{V}, &I_{D} = -5.3 \ \text{A} \\ &V_{GS} = -4.5 \ \text{V}, &I_{D} = -4 \ \text{A} \\ &V_{GS} = -10 \ \text{V}, &I_{D} = -5.3 \ \text{A} \\ &V_{GS} = -50 \ \text{V}, &I_{D} = -5.3 \ \text{A} \\ \end{split}$	-1	4.2 50 76 68	-3 59 92	V mV/°C
$\begin{array}{c ccc} V_{GS(th)} & G \\ \hline \Delta V_{GS(th)} & G \\ \hline \Delta T_J & T \\ \hline R_{DS(on)} & S \\ \hline G & G \\ \hline \\ G & G \\ \\ G & $	Gate Threshold Voltage Gate Threshold Voltage Femperature Coefficient Static Drain-Source Dn-Resistance Forward Transconductance Characteristics nput Capacitance	$\begin{split} I_D &= -250 \; \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{GS} &= -10 \; \text{V}, I_D = -5.3 \; \text{A} \\ V_{GS} &= -4.5 \; \text{V}, I_D = -4 \; \text{A} \\ V_{GS} &= -10 \; \text{V}, I_D = -5.3 \; \text{A}, T_J = 125^{\circ}\text{C} \\ V_{DS} &= -5\text{V}, \qquad I_D = -5.3 \; \text{A} \end{split}$	-1	4.2 50 76 68	59 92	mV/°C
$\begin{array}{c c} \underline{\Delta V_{GS(th)}} \\ \underline{\Delta T_J} \\ R_{DS(on)} \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\$	Gate Threshold Voltage Femperature Coefficient Static Drain–Source Dn–Resistance Forward Transconductance Characteristics nput Capacitance	$\begin{split} I_D &= -250 \; \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{GS} &= -10 \; \text{V}, I_D = -5.3 \; \text{A} \\ V_{GS} &= -4.5 \; \text{V}, I_D = -4 \; \text{A} \\ V_{GS} &= -10 \; \text{V}, I_D = -5.3 \; \text{A}, T_J = 125^{\circ}\text{C} \\ V_{DS} &= -5\text{V}, \qquad I_D = -5.3 \; \text{A} \end{split}$	-1	4.2 50 76 68	59 92	mV/°C
$\begin{array}{c c} \underline{\Delta V_{GS(th)}} \\ \underline{\Delta T_J} \\ R_{DS(on)} \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\$	Femperature Coefficient Static Drain–Source Dn–Resistance Forward Transconductance Characteristics nput Capacitance	$\begin{split} I_D &= -250 \; \mu\text{A}, \\ \text{Referenced to } 25^{\circ}\text{C} \\ V_{GS} &= -10 \; \text{V}, I_D = -5.3 \; \text{A} \\ V_{GS} &= -4.5 \; \text{V}, I_D = -4 \; \text{A} \\ V_{GS} &= -10 \; \text{V}, I_D = -5.3 \; \text{A}, T_J = 125^{\circ}\text{C} \\ V_{DS} &= -5\text{V}, \qquad I_D = -5.3 \; \text{A} \end{split}$		50 76 68	92	
RDS(on) SC G C G C C C Dynamic C C C iss Ir C coss C C rss R RG G Switching	Static Drain–Source Dn–Resistance Forward Transconductance Characteristics nput Capacitance	$\begin{aligned} &V_{GS} = -10 \text{ V}, & I_{D} = -5.3 \text{ A} \\ &V_{GS} = -4.5 \text{ V}, & I_{D} = -4 \text{ A} \\ &V_{GS} = -10 \text{ V}, I_{D} = -5.3 \text{ A}, T_{J} = 125^{\circ}\text{C} \\ &V_{DS} = -5\text{V}, &I_{D} = -5.3 \text{ A} \end{aligned}$		76 68	92	mΩ
g _{FS} F Dynamic C C _{iss} Ir C _{oss} C C _{rss} R R G Switching	Forward Transconductance Characteristics nput Capacitance	$V_{GS} = -4.5 \text{ V}, I_D = -4 \text{ A}$ $V_{GS} = -10 \text{ V}, I_D = -5.3 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{DS} = -5\text{V}, \qquad I_D = -5.3 \text{ A}$		68		
Dynamic C C C _{iss} Ir Ir C _{oss} C C C _{rss} R R Switching C	Characteristics nput Capacitance	$V_{DS} = -5V$, $I_{D} = -5.3 \text{ A}$			88	
Dynamic C C C _{iss} Ir Ir C _{oss} C C C _{rss} R R Switching C	Characteristics nput Capacitance			8.9	00	i
$\begin{array}{c c} C_{iss} & Ir \\ C_{oss} & C \\ C_{rss} & R \\ R_G & G \\ \hline \textbf{Switching} \end{array}$	nput Capacitance	<u> </u>				S
$\begin{array}{c c} C_{iss} & Ir \\ C_{oss} & C \\ C_{rss} & R \\ R_G & G \\ \hline \textbf{Switching} \end{array}$	nput Capacitance					
C _{rss} R R _G G	Output Capacitance			535		pF
R _G G Switching		$V_{DS} = -15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		135		pF
Switching	Reverse Transfer Capacitance	f = 1.0 MHz		75		pF
	Gate Resistance	$V_{GS} = 0 V$, $f = 1.0 MHz$		4.7		Ω
	Characteristics (Note 2)		1			
	Turn-On Delay Time			11	21	ns
t _r T	Γurn–On Rise Time	$V_{DD} = -15 \text{ V}, I_D = -1 \text{ A},$		16	28	ns
	Furn-Off Delay Time	$V_{GS} = -10 \text{ V}, I_D = -1 \text{ A},$ $V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$		15	26	ns
	Furn-Off Fall Time	1		10	19	ns
	Fotal Gate Charge			5.7	8	nC
	Gate-Source Charge	$V_{DS} = -15 \text{ V}, I_{D} = -5.3 \text{ A},$		1.8		nC
	Gate-Drain Charge	$V_{GS} = -5 \text{ V}$		2.4		nC
	urce Diode Characteristics a	and Maximum Datings				
	Vaximum Continuous Drain-Source	•			-1.3	Α
V _{SD} D	Orain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -1.3 \text{ A} \text{(Note 2)}$		-0.8	-1.2	V
Schottky F	Diode Characteristics					
	Reverse Leakage	V _R = 30 V		160	500	μА
	Forward Voltage	T _J = 25°C		225	280	mV
		$T_{J} = 0.1A$ $T_{J} = 125^{\circ}C$		80	250	mV
V_{F} F		$I_F = 1A$ $T_J = 25^{\circ}C$		305	350	mV
		$T_{\rm J} = 125^{\circ}{\rm C}$		185 380	250 420	mV

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	135	°C/W
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Notes

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



78°C/W when mounted on a 0.5in² pad of 2 oz copper



125°C/W when mounted on a 0.02 in² pad of 2 oz copper



135°C/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

Typical Characteristics

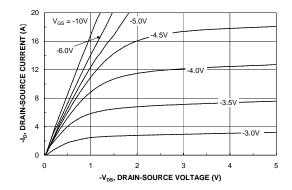


Figure 1. On-Region Characteristics.

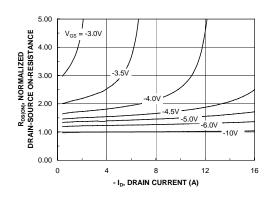


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

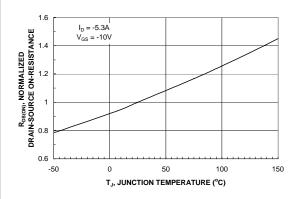


Figure 3. On-Resistance Variation with Temperature.

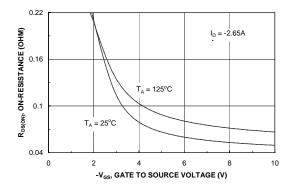


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

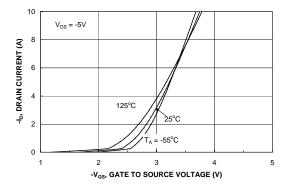


Figure 5. Transfer Characteristics.

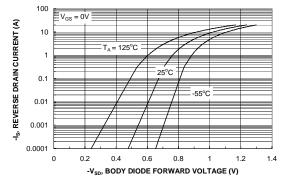
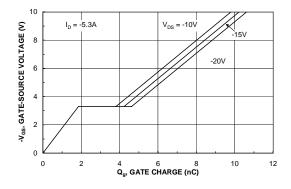


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



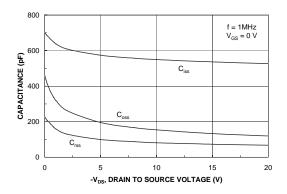
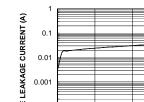
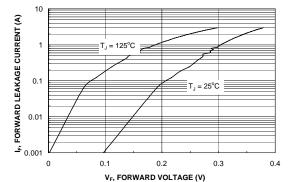


Figure 8. Capacitance Characteristics.

Figure 7. Gate Charge Characteristics.





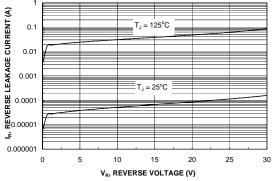


Figure 9. Schottky Diode Forward Voltage.



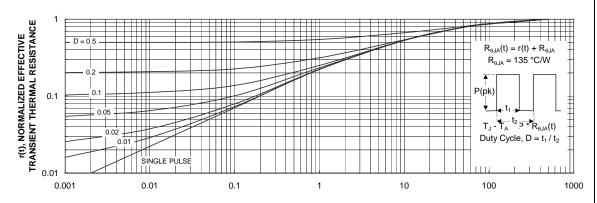


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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CROSSVOLT™	FRFET™	MicroPak™	QFET™	SuperSOT™-8
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EcoSPARK™	GTO™ .	MSX™	QT Optoelectronics™	TinyLogic™
E ² CMOS TM	HiSeC™	MSXPro™	Quiet Series™	TruTranslation™
EnSigna™	I ² C TM	OCX™	RapidConfigure™	UHC™
Across the board.	Around the world.™	OCXPro™	RapidConnect™	UltraFET [®]
The Power Franch	nise™	OPTOLOGIC®	SILENT SWITCHER®	VCX™
Programmable Ac	tive Droop™	OPTOPLANAR™	SMART START™	

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